

NOTES:

1. SUBSTRATE: UV FUSED SILICA
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED

T(avg): ≥91% FROM 1095 - 1650nm @ 0° AOI

T(avg): ≤0.01% FROM 200 - 1055nm @ 0° AOI

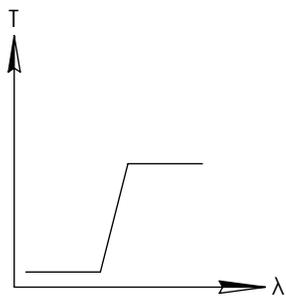
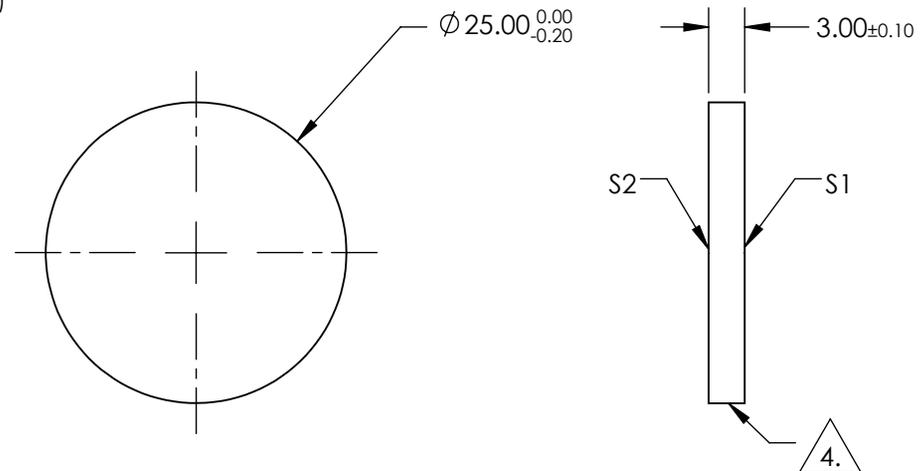
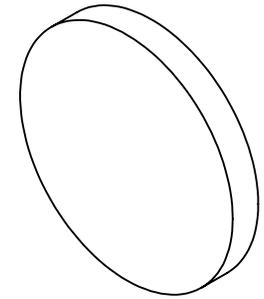
T(abs): =50% FOR 1075±10.75nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm (prior to coating)
7. ROHS COMPLIANT

FOR INFORMATION ONLY:  
DO NOT MANUFACTURE  
PARTS TO THIS DRAWING

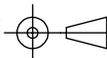


LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
DIMENSIONS ARE FOR REFERENCE ONLY

	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	60-40	60-40
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

THIRD ANGLE PROJECTION



ALL DIMS IN

mm

**EO**® Edmund Optics®

TITLE

Ø25mm, 1075nm, HIGH PERFORMANCE  
LONGPASS FILTER

DWG NO

86075

SHEET  
1 OF 1